

[Web](#) [Images](#) [Groups](#) [News](#) [Froogle](#) [more »](#)["Integral Solutions International" + "simula](#)[Search](#)[Advanced Search](#)[Preferences](#)**Web** Results 1 - 6 of about 7 English pages for "[Integral Solutions International](#)" + "[simulation](#)". (0.27 sec)

Tip: Try removing quotes from your search to get more results.

[Yahoo! Directory California > San Francisco Bay Area > Electronic ...](#)... **Integral Solutions International** - San Jose - manufacturer of test equipment for ...Technology - Berkeley - develops 3D electromagnetic **simulation** software for ...[dir.yahoo.com/.../Business\\_and\\_Shopping/](#)[Business\\_to\\_Business/Electronics/Test\\_and\\_Measurement\\_Equipment/](#) - 36k - [Cached](#) - [Similar pages](#)[Yahoo! Regional > US States > California > Metropolitan Areas > ...](#)... **Integral Solutions International** Open site in a new window - San Jose ... site in a new window - Berkeley - develops 3D electromagnetic **simulation** software for ...[sg.dir.yahoo.com/.../Business\\_and\\_Shopping/](#)[Business\\_to\\_Business/Electronics/Test\\_and\\_Measurement\\_Equipment/](#) - 29k - [Supplemental](#)[Result](#) - [Cached](#) - [Similar pages](#)[\[PDF\] A Comparison of Quasi-Static Characteristics and Failure ...](#)File Format: PDF/Adobe Acrobat - [View as HTML](#)

... using a new system combining quasi-static (QST) analysis with in-situ CDM and HBM

**ESD simulation** capabilities. ... [5] **Integral Solutions International**, San Jose ...[www.isiguy.com/Publications/CDM%20vs%20HBM%20Article.pdf](#) - [Similar pages](#)

## 1999 EOS

... 2A.7 A **Simulation** Analysis of Quarter-Micron CMOS LSI Input Circuit ... Heads as a function of Temperature, C.Moore, **Integral Solutions International**; A. Wallash ...[www.esd-china.com/htm/1999esd.htm](#) - 17k - [Cached](#) - [Similar pages](#)[\[PDF\] inside inside](#)File Format: PDF/Adobe Acrobat - [View as HTML](#)

Page 1. International Disk Drive Equipment and Materials Association inside

7 8 18 26 44 49 what's The Disk Drive Market: A Period ...

[www.idema.org/files/public/insight\\_sept99.pdf](#) - [Similar pages](#)

## Electrostatic Discharge Association

... of GMR Heads subjected to CDM and HBM ESD Events C. Moore, **Integral Solutions International**. ... QST) analysis with in-situ CDM and HBM **ESD simulation** capabilities. ...[www.esda.org/symp\\_techsess.html](#) - 57k - [Supplemental](#) - [Cached](#) - [Similar pages](#)*In order to show you the most relevant results, we have omitted some entries very similar to the 6 already displayed.**If you like, you can [repeat the search with the omitted results included](#).*Free! Get the Google Toolbar. [Download Now](#) - [About Toolbar](#)[Search Web](#)

49 Pop-ups blocked

News

Autofill



[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2004 Google

# Dial g DataStar

[options](#)[logoff](#)[feedback](#)[help](#)[databases](#)[easy](#)[search](#)

## Advanced Search: INSPEC - 1969 to date (INZZ)

[first](#)

Search history:

No.	Database	Search term	Info added since	Results	
1	INZZ	charged ADJ device ADJ model OR CDM	unrestricted	2106	<a href="#">show titles</a>
2	INZZ	CDM AND mercury ADJ switch	unrestricted	0	-
3	INZZ	1 AND simulation	unrestricted	362	<a href="#">show titles</a>
4	INZZ	3 AND wet	unrestricted	0	-

[hide](#) | [delete all search steps...](#) | [delete individual search steps...](#)
Enter your search term(s): [Search tips](#) whole document
 Information added since:  or:  [none](#) 
  
(YYYYMMDD)

Select special search terms from the following list(s):

- Classification codes A: Physics, 0-1
- Classification codes A: Physics, 2-3
- Classification codes A: Physics, 4-5
- Classification codes A: Physics, 6
- Classification codes A: Physics, 7
- Classification codes A: Physics, 8
- Classification codes A: Physics, 9
- Classification codes B: Electrical & Electronics, 0-5
- Classification codes B: Electrical & Electronics, 6-9
- Classification codes C: Computer & Control
- Classification codes D: Information Technology
- Classification codes E: Manufacturing & Production
- Treatment codes

INSPEC sub-file



[Publication types](#)



[Language of publication](#)

[Top](#) - [News & FAQS](#) - [Dialog](#)

© 2004 Dialog



Web Images Groups News Froogle more »

"CDM simulator"

Search

Advanced Search

Preferences

## Web

Results 11 - 19 of about 22 English pages for "CDM simulator". (0.13 seconds)

### Products-INDEX

notice about ESD and clean room package chairs. ESD package chairs discharge the electro-static charge of the human body by a safe ...

[www.tet.co.jp/English/products/](http://www.tet.co.jp/English/products/) - 26k - Cached - Similar pages

### ATM R&D Project Synopses

... movement Planning Ref: EEC. 10/2003, Y. RDI, R&D Infrastructure. **CDM Simulator**

Development Ref: EEC. 12/2003, Y. Responsible Organisation ...

[www.eurocontrol.int/ardep-arda/jsp/Ardep014.jsp?Proj=EUR083](http://www.eurocontrol.int/ardep-arda/jsp/Ardep014.jsp?Proj=EUR083) - 46k - Cached - Similar pages

### ESD Test Equipment - July 1995

... The **CDM simulator** typically charges a device lying upside down on a 1/32"-thick insulating material by applying a voltage through a high-resistance probe and ...

[www.evaluationengineering.com/archive/articles/0795esd.htm](http://www.evaluationengineering.com/archive/articles/0795esd.htm) - 16k - Cached - Similar pages

### product

代理產品. 代理廠商(美國/韓國). 代理產品. INDUSTRIAL EQUIPMENT. **CDM SIMULATOR**. IRDA TEST SYSTEM. OPEN/SHORT TESTER. ESD TESTER. ESD & LATCH-UP TESTER. ...

[www.pdt.com.tw/product.htm](http://www.pdt.com.tw/product.htm) - 16k - Cached - Similar pages

[ More results from [www.pdt.com.tw](http://www.pdt.com.tw) ]

### N MIN MAX 0 4000.0 0.0 : Number of macroparticles in the beam. 0 ...

N MIN MAX 0 4000.0 0.0 ; Number of macroparticles in the beam. 0 0.0 0.0 ; Charge of macroparticles in e-charge. 0 3.0E6 0.0 ; Light duration (ps). ...

[www.inp.nsk.su/~logatcho/cdm/simulator/varpar.dat](http://www.inp.nsk.su/~logatcho/cdm/simulator/varpar.dat) - 2k - Cached - Similar pages

[ More results from [www.inp.nsk.su](http://www.inp.nsk.su) ]

### 德技股份有限公司

>>ESD Measurement Products>>ESD/CDM Simulator, Manufacturer, TOKYO ELECTRONICS TRADING CO. LTD. 日本 <http://www.tet.co.jp>. Model NO. ...

[www.quatek.com.tw/english/product3.asp?pdiden=38&pdid=258](http://www.quatek.com.tw/english/product3.asp?pdiden=38&pdid=258) - 8k - Supplemental Result - Cached - Similar pages

### 德技股份有限公司

Webmaster : This site is designed for Internet Explorer and an 800x600 resolution.

If you have any question or find any problem, please ...

[www.quatek.com.tw/english/product2.asp?pdiden=38](http://www.quatek.com.tw/english/product2.asp?pdiden=38) - 8k - Supplemental Result -

Cached - Similar pages

### Home Page of Andrew McCormick

Andrew McCormick's Home Page. Communications and Signal Processing Research. OFDM and Multi-Carrier CDMA. My current research interests ...

[www.scc.ed.ac.uk/~acmc/index2.html](http://www.scc.ed.ac.uk/~acmc/index2.html) - 4k - Cached - Similar pages

### Charged Device

... THE **CDM SIMULATOR**: At a standard charged device modelling simulator the device under test is placed on dielectric, charged by a power supply and discharged ...

[www.spectrum-et.com/charged\\_device.html](http://www.spectrum-et.com/charged_device.html) - 6k - Supplemental Result - Cached - Similar pages

*In order to show you the most relevant results, we have omitted some entries very similar to the 19 already displayed.*

*If you like, you can repeat the search with the omitted results included.*

  
Result Page: [Previous](#) [1](#) [2](#)

[Search within results](#) | [Language Tools](#) | [Search Tips](#)

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2004 Google

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)Welcome  
United States Patent and Trademark Office

» See

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)**Quick Links****Welcome to IEEE Xplore®**

- Home
- What Can I Access?
- Log-out

**Tables of Contents**

- Journals & Magazines
- Conference Proceedings
- Standards

**Search**

- By Author
- Basic
- Advanced

**Member Services**

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

**IEEE Xplore®**

- Access the IEEE Enterprise File Cabinet

**Print Format**

Your search matched **6** of **1074479** documents.  
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

**Refine This Search:**

You may refine your search by editing the current search expression or enter new one in the text box.

 gorin<and>testing Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Coherent addition of intermodulation distortion in spectrum analysis**

Stepanek, P.; Kurtz, D.; Gorin, J.;

Microwave Symposium Digest, 2003 IEEE MTT-S International , Volume: 2 , 8 June 2003

Pages:1415 - 1417 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(261 KB\)\]](#) **IEEE CNF****2 A reconfigurable fault-tolerant signal processor**

Shively, R.R.; Gorin, A.L.;

Acoustics, Speech, and Signal Processing, 1989. ICASSP-89., 1989 International Conference on , 23-26 May 1989

Pages:2397 - 2400 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(336 KB\)\]](#) **IEEE CNF****3 A scintillating fiber tracker with high time resolution for high-rate experiments**

Horikawa, S.; Daito, I.; Doshita, N.; Gorin, A.; Hasegawa, T.; Horikawa, N.; I T.; Kondo, K.; Kuroda, K.; Manuilov, I.; Matsuda, T.; Miyachi, Y.; Riazantsev, Takabayashi, N.; Toeda, T.; Torimitsu, S.;

Nuclear Science, IEEE Transactions on , Volume: 49 , Issue: 3 , June 2002

Pages:950 - 956

[\[Abstract\]](#) [\[PDF Full-Text \(357 KB\)\]](#) **IEEE JNL****4 A scintillating fiber tracker with high time resolution for high-rate experiments**

Horikawa, S.; Daito, I.; Doshita, N.; Horikawa, N.; Iwata, T.; Kondo, K.; Miyachi, Y.; Takabayashi, N.; Toeda, T.; Torimitsu, S.; Gorin, A.; Manuilov, I.; Riazantsev, S.;

A.; Hasegawa, T.; Matsuda, T.; Kuroda, K.-I.;  
Nuclear Science Symposium Conference Record, 2001 IEEE , Volume: 1 , 4-1  
Nov. 2001  
Pages:559 - 563 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(992 KB\)\]](#) [IEEE CNF](#)

---

**5 Analysis of current distribution in the zone of high speed sliding contact of the pulsed electromechanical converters**

Chemerys, V.T.; Gorin, V.V.;  
Pulsed Power Plasma Science, 2001. IEEE Conference Record - Abstracts , 17  
June 2001  
Pages:530

[\[Abstract\]](#) [\[PDF Full-Text \(36 KB\)\]](#) [IEEE CNF](#)

---

**6 Adaptive language acquisition using incremental learning**

Farrell, K.; Mamnone, R.J.; Gorin, A.L.;  
Acoustics, Speech, and Signal Processing, 1993. ICASSP-93., 1993 IEEE  
International Conference on , Volume: 1 , 27-30 April 1993  
Pages:501 - 504 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(304 KB\)\]](#) [IEEE CNF](#)

---

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) |  
[New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

# Dial-a-DataStar

[options](#)[logoff](#)[feedback](#)[help](#)[databases](#)[easy search](#)

## Advanced Search: INSPEC - 1969 to date (INZZ)

[limit](#)

Search history:

No.	Database	Search term	Info added since	Results	
1	INZZ	moore-c\$	unrestricted	1289	<a href="#">show titles</a>
2	INZZ	1 AND testing AND electrical	unrestricted	6	<a href="#">show titles</a>
3	INZZ	(integral ADJ solutions).IN.	unrestricted	10	<a href="#">show titles</a>
4	INZZ	3 AND simulation	unrestricted	2	<a href="#">show titles</a>
5	INZZ	goring-i\$	unrestricted	0	-
6	INZZ	gorin-i\$	unrestricted	0	-

[hide](#) | [delete all search steps...](#) | [delete individual search steps...](#)
Enter your search term(s): [Search tips](#) whole document
 Information added since:  or:  [none](#)  
 (YYYYMMDD)
[search](#)

Select special search terms from the following list(s):

- Classification codes A: Physics, 0-1
- Classification codes A: Physics, 2-3
- Classification codes A: Physics, 4-5
- Classification codes A: Physics, 6
- Classification codes A: Physics, 7
- Classification codes A: Physics, 8
- Classification codes A: Physics, 9
- Classification codes B: Electrical & Electronics, 0-5
- Classification codes B: Electrical & Electronics, 6-9
- Classification codes C: Computer & Control
- Classification codes D: Information Technology
- Classification codes E: Manufacturing & Production

-  Treatment codes
-  INSPEC sub-file
-  Publication types
-  Language of publication

[Top](#) ~ [News & FAQS](#) ~ [Dialog](#)

© 2004 Dialog

	Type	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L1	3	CDM same simulator	USPAT	2004/09/24 15:05
2	BRS	L2	3	CDM same simulator	USPAT	2004/09/24 15:07
3	BRS	L3	246	(wet same relay) and (relay same switch)	USPAT	2004/09/24 15:08
4	BRS	L4	1	(wet same relay) and (relay same switch) and simulation and	USPAT	2004/09/24 15:09
5	BRS	L5	1	(wet same mercury) and (relay same switch) and simulation and	USPAT	2004/09/24 15:12
6	BRS	L6	0	(dielectric adj layer) and (rapid adj discharge) and simulator	USPAT	2004/09/24 15:13
7	BRS	L7	47	(dielectric adj layer) and (rapid adj discharge)	USPAT	2004/09/24 15:13
8	BRS	L8	2	(dielectric adj layer) same (rapid adj discharge)	USPAT	2004/09/24 15:14
9	BRS	L9	715	test same (electrical adj device)	USPAT	2004/09/24 15:14
10	BRS	L10	1081	((magnetic adj head) same test)	USPAT	2004/09/24 15:16
11	BRS	L11	1356	((magnetic adj head) same test\$)	USPAT	2004/09/24 15:16
12	BRS	L12	1	((magnetic adj head) same test\$) same (dielectric adj layer)	USPAT	2004/09/24 15:17
13	BRS	L13	23	CDM same simulate\$	USPAT	2004/09/24 15:18
14	BRS	L14	8	CDM same simulate\$ and node\$	USPAT	2004/09/24 15:18
15	BRS	L16	1	CDM same simulate\$ and (node\$ and resistor\$) and inductance	USPAT	2004/09/24 15:19
16	BRS	L15	7	CDM same simulate\$ and (node\$ and resistor\$)	USPAT	2004/09/24 15:27
17	BRS	L17	456	JEDEC adj STANDARD	USPAT	2004/09/24 15:28
18	BRS	L18	1	(JEDEC adj STANDARD) same simulation	USPAT	2004/09/24 15:28
19	BRS	L19	3	(JEDEC adj STANDARD) and CDM	USPAT	2004/09/24 15:29